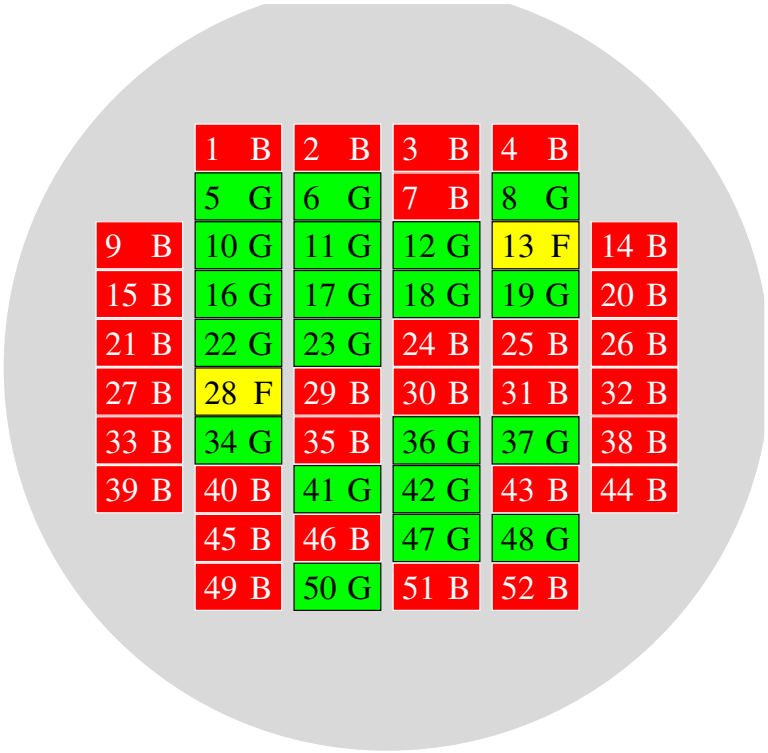
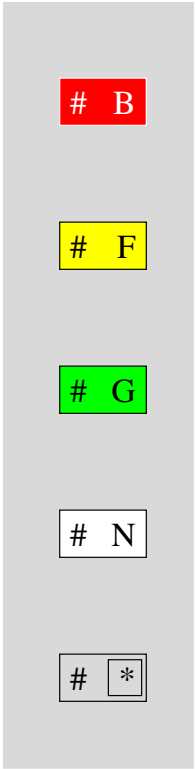
Die quality map for wafer 127 s/n: 21316-05-18

Date: 02/26/99





Bad die

Fair die

Good die

No info

Manually tagged